Our standard IOL system is abble to test low power devices soldered on substrate as well as high power devices. System can handle p-channel or n-channel MOS, IGBT and diodes and consist of two parts.

## CALIBRATING EQUIPMENT:

This calibrating equipment is necessary above all for low power smd devices because the data sheet thermal resistance Rth is almost allways different of actual Rth of DUT on test board

This equipment offers following features :

Test capacity : 80 DUTs

Operating systems : MS Windows XP

Possible modes : - calibration

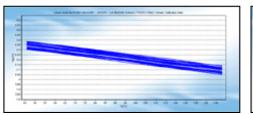
- IOL test by high temperature, f.e. between 150°C and 200°C Measurement : - Thermal dependance of Vgs, Rds(on) and Vr(diode)

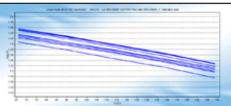
- Actual thermal resistance Rth of all DUTs on test board

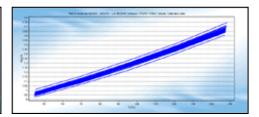
Handling : Comfortable graphic platform

After calibration system offers calibrating datas for IOL test and graphs of thermal dependance of different parameters, so that operator can see, which parameter is the best for the measurement of junction temperature Tj during the following IOL test









## **IOL TEST SYSTEM :**

This equipment offers following features :

Test capacity : 3 lots with 80 DUTs per lot

constant power with accuracy of 1% Test condition : constant current with accuracy of 1%

Current range : Autoranging 20mA to 2A or 20mA to 20A

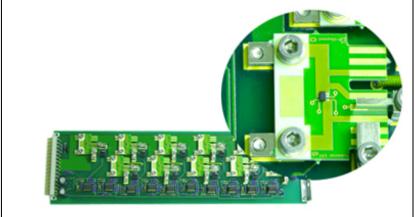
Junction temperature of each DUT every 50ms Measurement : Load current and voltage of each DUT every 50ms Case temperature measurement over PT100

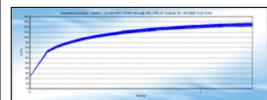
Power supplies : Programmable 15V/200A for each lot

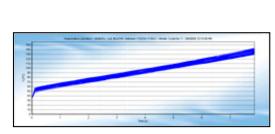
Operating system : MS Windows XP

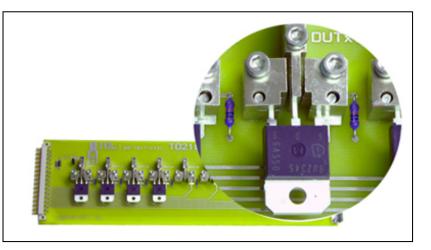
Handling : Comfortable graphic platform











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